Supporting Information

Effect of thermal treatment temperature of RuNi bimetallic nanocatalyst on its catalytic performance for benzene hydrogenation

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Ref	Catalyst	t (h)	P (H ₂) (MPa)	T(℃)	TOF (h ⁻¹)	Yield to cyclohexane
1	2mol%Perfluoro-tagged Ru1	0.5	0.1	60	29	34%
2	4.2wt%Ru/C-silica 2	0.53	8.0	110	37700	99.8%
3	0.27%Ru/NFS ³	2.25	0.29	25	5430	100%
4	3.3wt%Ru/MMT ⁴	2.5	8	110	4000	100%
5	4.6%Ru/rGO ⁵	1	4.0	130	38000	61.3%
6	Ru/CNTs ⁶	0.5	4.0	80	6983	99.97%
7	0.1wt%Pd/SiO ₂ ⁷	2	0.83	140	10000	14%
8	Ir NPs@zeolite ⁸	8	0.3	25	3190	100%
9	Rh/HEA-C169	5	0.1	20	60	100%
10	11.2wt%Rh/MWNTs10	3	1	20	1038	80%
11	0.7wt%Rh(cod)-9.86wt%Pd/SiO ₂ ¹¹	2	3	40	1241	52%
12	6.3wt%Pd-6.9wt%Rh/CNT12	24	1	20	592.6	100%
13	$Rh_{0.5}Ni_{0.5}{}^{13}$	7	4.0	25	290	50.8%
This work	RuNi/C~680~PVP	1	5.3	60	5300	29.1%
This work	RuNi/C~380	1	5.3	60	7750	42.5%

Table S1 Catalytic performance of unsupported and supported metal catalysts for

 benzene hydrogenation to cyclohexane reported in the literatures

As shown in Table S1, the RuNi/C~680~PVP catalyst exhibited relatively high catalytic performance in benzene hydrogenation reaction compared to a number of supported and unsupported Ru-based, Rh-based, Pd-based, Ir-based and bimetallic-based catalysts reported in the literatures.



Fig. S1 XRD patterns for the RuNi/C~X~PVP samples. (a) carbon~380, (b) 2.5%Ru/C~600~N₂+H₂, (c) RuNi/C~380~PVP, (d) RuNi/C~480~PVP, (e) RuNi/C~580~PVP and (f) RuNi/C~680~PVP. The blue, red and black arrows represent the characteristic diffraction peaks of Ru, RuO₂ and Ni crystallite phase, respectively. The two broad peaks at $2\theta = 24^{\circ}$, 43° in the XRD patterns are attributed to carbon(002) and (100).¹⁴⁻¹⁶

Fig. S1a shows the characteristic peaks of hcp Ru (JCPDS card No. 06-0663). For the RuNi/C~X~PVP catalysts, only the diffraction peaks of carbon(002) and carbon(100) can be observed in the XRD patterns when the annealing temperature below or equal to 380 °C, indicating that the Ni, NiO, Ru or RuNi nanoparticles (NPs) were either very small or amorphous, and with high dispersion. When RuNi/C~uncalcined~PVP treated in flowing N₂ at 480 °C for 3 h, the NiO(200) (2 θ =43.3°) (JCPDS card No. 47-1049), RuO₂(101) (2 θ =35.0°) and RuO₂(211) (2 θ =54.3°) (JCPDS card No. 43-1027) diffraction peaks are present in Fig. S1d. With the thermal treatment temperature continuously increasing to 580 °C or 680 °C, the Ni and Ru species mainly appeared

with the form of reduced state Ni(0) and Ru(0) owing to the reducing capacity of carbon black at high temperature.



Fig. S2 (A) Ni 2p XPS and (B) Ru 3p spectra for (a) RuNi/C~380~PVP, (b) RuNi/C~480~PVP and (c) RuNi/C~680~PVP.



Fig. S3 (a) HRTEM image for the Ni/NiO/C sample and (b) Enlarged view of the selected area in image a. The indicated lattice fringes, 0.202 nm and 0.243 nm, corresponding to Ni(111) planes (JCPDS card No. 04-0850) and NiO(111) (JCPDS card No. 47-1049), respectively. The inset in (b) shows fast Fourier transform (FFT) patterns results. It indicates that Ni/NiO NPs are small and also with high dispersion.



Fig. S4 (A) TEM and (B) HRTEM images for the 1.25%Ru/C~380~N₂+H₂ sample. The indicated lattice fringes-0.206 nm corresponds to Ru(101) facets (JCPDS card No. 06-0663). The inset in (b) shows fast Fourier transform (FFT) patterns results. It suggests that Ru NPs are highly dispersed on the support, without any agglomeration.



Fig. S5 (A-D) TEM images for the RuNi/C~uncalcined~PVP sample. (E, F) HRTEM images for the RuNi/C~uncalcined~PVP sample.



Fig. S6 (A) TEM image and (B) RuNi BNPs size distribution for the RuNi/C~160 sample. By counting more than 100 RuNi NPs, the size distribution and mean size of RuNi NPs were obtained. The size distribution was very narrow and the average size was about 1.82 nm.



Fig. S7 (A) HRTEM image for the RuNi/C~160 sample. Scale bar, 10 nm. (B) Enlarged view of the selected area in image A. Scale bar, 2 nm. The indicated lattice fringes, 0.270 nm, corresponding to Ni(OH)₂(100) facets (JCPDS card No. 14-0117). The inset in (b) shows fast Fourier transform (FFT) patterns results. It indicates that Ni(OH)₂ remained in the sample due to the low annealing temperature (160 °C).

Notes and references

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